

Notice of References Cited	Application/Control No. 10/614,031	Applicant(s)/Patent Under Reexamination PAN ET AL.	
	Examiner Andre' C. Stevenson	Art Unit 2812	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-4,782,302	11-1988	Bastasz et al.	324/71.3
	B	US-5,219,769	06-1993	Yonehara et al.	438/105
	C	US-6,903,433	06-2005	McFarland et al.	257/471
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	"Characteristics of Al/p-CuAgInSe Polycrystalline Thin Film Schottky Barrier Diodes; G Venkata Rao; March 6, 2001Thin Film Laboratory, Department of Physics, Sri Venkateswara University; Pages571-576
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.